

IS61C512

64K x 8 HIGH-SPEED CMOS STATIC RAM

AUGUST 1995

FEATURES

- Pin compatible with 128K x 8 devices
- High-speed access time: 15, 20, 25, 35 ns
- Low active power: 500 mW (typical)
- Low standby power
— 250 μ W (typical) CMOS standby
- Output Enable (\overline{OE}) and two Chip Enable ($\overline{CE1}$ and $\overline{CE2}$) inputs for ease in applications
- Fully static operation: no clock or refresh required
- TTL compatible inputs and outputs
- Single 5V ($\pm 10\%$) power supply

DESCRIPTION

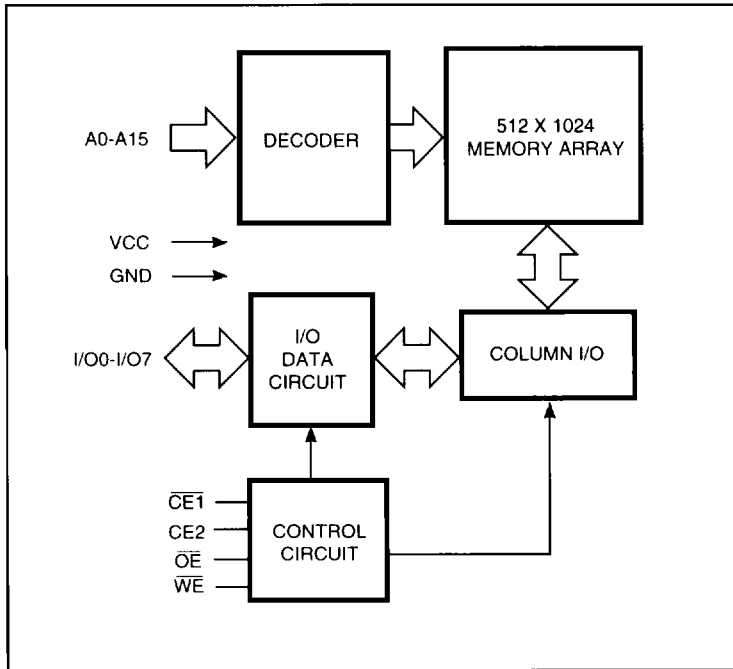
The ISSI IS61C512 is a very high-speed, low power, 65,536 word by 8-bit CMOS static RAMs. They are fabricated using ISSI's high-performance CMOS technology. This highly reliable process coupled with innovative circuit design techniques, yields higher performance and low power consumption devices.

When $\overline{CE1}$ is HIGH or $\overline{CE2}$ is LOW (deselected), the device assumes a standby mode at which the power dissipation can be reduced down to 1 mW (typical) with CMOS input levels.

Easy memory expansion is provided by using two Chip Enable inputs, $\overline{CE1}$ and $\overline{CE2}$. The active LOW Write Enable (\overline{WE}) controls both writing and reading of the memory.

The IS61C512 is available in 32-pin 300-mil and 400-mil plastic DIP and SOJ packages.

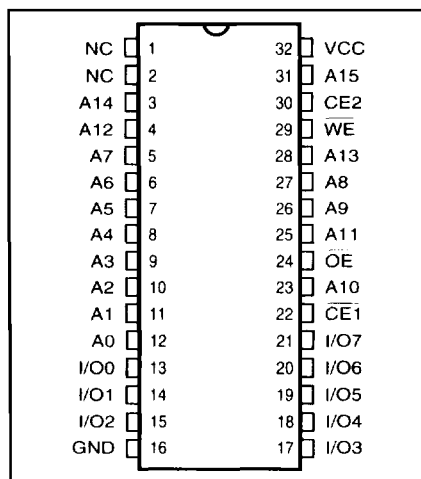
FUNCTIONAL BLOCK DIAGRAM



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PIN CONFIGURATION

32-Pin DIP and SOJ



PIN DESCRIPTIONS

A0-A15	Address Inputs
$\overline{CE1}$	Chip Enable 1 Input
CE2	Chip Enable 2 Input
\overline{OE}	Output Enable Input
\overline{WE}	Write Enable Input
I/O0-I/O7	Input/Output
Vcc	Power
GND	Ground

TRUTH TABLE

Mode	\overline{WE}	$\overline{CE1}$	CE2	\overline{OE}	I/O Operation	Vcc Current
Not Selected	X	H	X	X	High-Z	ISB1, ISB2
(Power-down)	X	X	L	X	High-Z	ISB1, ISB2
Output Disabled	H	L	H	H	High-Z	Icc1, Icc2
Read	H	L	H	L	DOUT	Icc1, Icc2
Write	L	L	H	X	DIN	Icc1, Icc2

ABSOLUTE MAXIMUM RATINGS⁽¹⁾

Symbol	Parameter	Value	Unit
V _{TERM}	Terminal Voltage with Respect to GND	-0.5 to +7.0	V
T _{BIAS}	Temperature Under Bias	-55 to +125	°C
T _{STG}	Storage Temperature	-65 to +150	°C
P _T	Power Dissipation	1.5	W
I _{OUT}	DC Output Current (LOW)	20	mA

Notes:

1. Stress greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

OPERATING RANGE

Range	Ambient Temperature	Vcc
Commercial	0°C to +70°C	5V ± 10%
Industrial ⁽¹⁾	-40°C to +85°C	5V ± 10%

Notes:

1. Industrial supplement specification available upon request.

DC ELECTRICAL CHARACTERISTICS (Over Operating Range)

Symbol	Parameter	Test Conditions	Min.	Max.	Unit
V _{OH}	Output HIGH Voltage	V _{CC} = Min., I _{OH} = -4.0 mA	2.4	—	V
V _{OL}	Output LOW Voltage	V _{CC} = Min., I _{OL} = 8.0 mA	—	0.4	V
V _{IH}	Input HIGH Voltage		2.2	V _{CC} + 0.5	V
V _{IL}	Input LOW Voltage ⁽¹⁾		-0.3	0.8	V
I _{LI}	Input Leakage	GND ≤ V _{IN} ≤ V _{CC}	-2	2	μA
I _{LO}	Output Leakage	GND ≤ V _{OUT} ≤ V _{CC} , Outputs Disabled	-2	2	μA

Notes:

- V_{IL} = -3.0V for pulse width less than 10 ns.

POWER SUPPLY CHARACTERISTICS⁽¹⁾ (Over Operating Range)

Symbol	Parameter	Test Conditions	-15 ns		-20 ns		-25 ns		-35 ns		Unit
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
I _{CC1}	V _{CC} Operating Supply Current	V _{CC} = Max., I _{OUT} = 0 mA, f = 0	—	120	—	120	—	120	—	120	mA
I _{CC2}	V _{CC} Dynamic Operating Supply Current	V _{CC} = Max., I _{OUT} = 0 mA, f = f _{MAX}	—	180	—	165	—	150	—	130	mA
I _{SB1}	TTL Standby Current (TTL Inputs)	V _{CC} = Max., V _{IN} = V _{IH} or V _{IL} CE1 ≥ V _{IH} or CE2 ≤ V _{IL} , f = 0	—	40	—	40	—	40	—	40	mA
I _{SB2}	CMOS Standby Current (CMOS Inputs)	V _{CC} = Max., CE1 ≥ V _{CC} - 0.2V, CE2 ≤ 0.2V, V _{IN} ≥ V _{CC} - 0.2V, or V _{IN} ≤ 0.2V, f = 0	—	5	—	5	—	5	—	5	mA

Notes:

- At f = f_{MAX}, address and data inputs are cycling at the maximum frequency, f = 0 means no input lines change.

CAPACITANCE^(1,2)

Symbol	Parameter	Conditions	Max.	Unit
C _{IN}	Input Capacitance	V _{IN} = 0V	5	pF
C _{OUT}	Output Capacitance	V _{OUT} = 0V	7	pF

Notes:

- Tested initially and after any design or process changes that may affect these parameters.
- Test conditions: T_A = 25°C, f = 1 MHz, V_{CC} = 5.0V.

READ CYCLE SWITCHING CHARACTERISTICS⁽¹⁾ (Over Operating Range)

Symbol	Parameter	-15 ns		-20 ns		-25 ns		-35 ns		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{RC}	Read Cycle Time	15	—	20	—	25	—	35	—	ns
t _{AA}	Address Access Time	—	15	—	20	—	25	—	35	ns
t _{OHA}	Output Hold Time	3	—	3	—	3	—	3	—	ns
t _{ACE1}	$\overline{CE1}$ Access Time	—	15	—	20	—	25	—	35	ns
t _{ACE2}	CE2 Access Time	—	15	—	20	—	25	—	35	ns
t _{DOE}	\overline{OE} Access Time	—	7	—	8	—	9	—	12	ns
t _{LZOE⁽²⁾}	\overline{OE} to Low-Z Output	0	—	0	—	0	—	0	—	ns
t _{HZOE⁽²⁾}	\overline{OE} to High-Z Output	0	6	0	9	0	10	0	12	ns
t _{LZCE1⁽²⁾}	$\overline{CE1}$ to Low-Z Output	2	—	3	—	3	—	3	—	ns
t _{LZCE2⁽²⁾}	CE2 to Low-Z Output	2	—	3	—	3	—	3	—	ns
t _{HZCE⁽²⁾}	$\overline{CE1}$ or CE2 to High-Z Output	0	8	0	9	0	10	0	12	ns
t _{PU⁽³⁾}	$\overline{CE1}$ or CE2 to Power-Up	0	—	0	—	0	—	0	—	ns
t _{PD⁽³⁾}	$\overline{CE1}$ or CE2 to Power-Down	—	12	—	18	—	20	—	20	ns

Notes:

1. Test conditions assume signal transition times of 5 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V and output loading specified in Figure 1a.
2. Tested with the load in Figure 1b. Transition is measured ± 500 mV from steady-state voltage. Not 100% tested.
3. Not 100% tested.

AC TEST CONDITIONS

Parameter	Unit
Input Pulse Level	0V to 3.0V
Input Rise and Fall Times	3 ns
Input and Output Timing and Reference Level	1.5V
Output Load	See Figures 1a and 1b

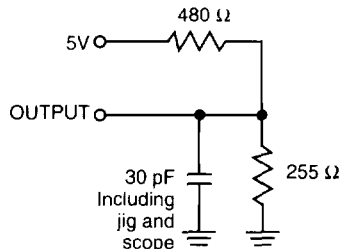
AC TEST LOADS

Figure 1a.

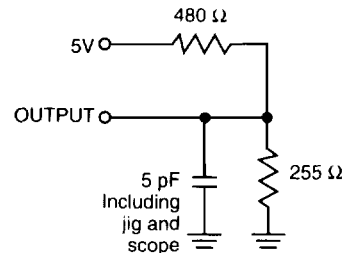
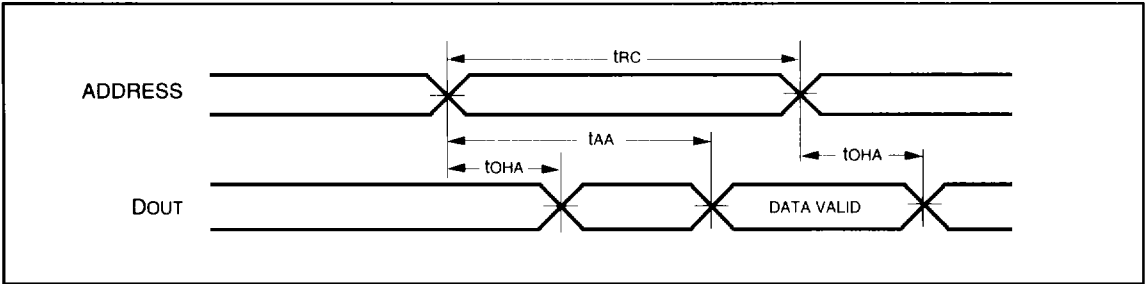


Figure 1b.

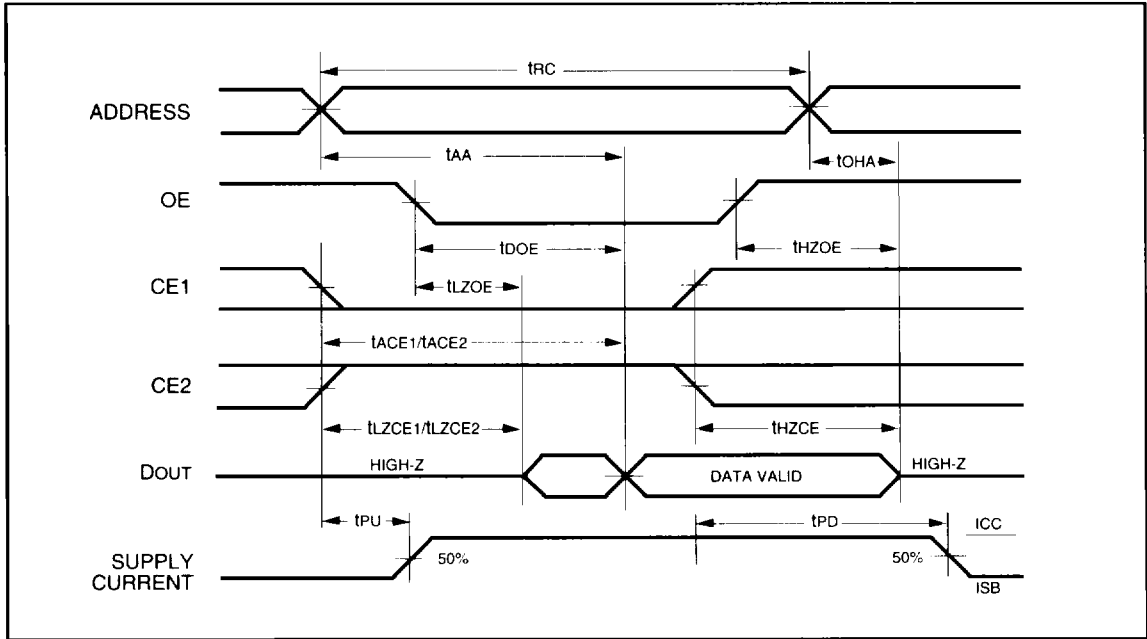
AC WAVEFORMS

READ CYCLE NO. 1^(1,2)



2

READ CYCLE NO. 2^(1,3)



Notes:

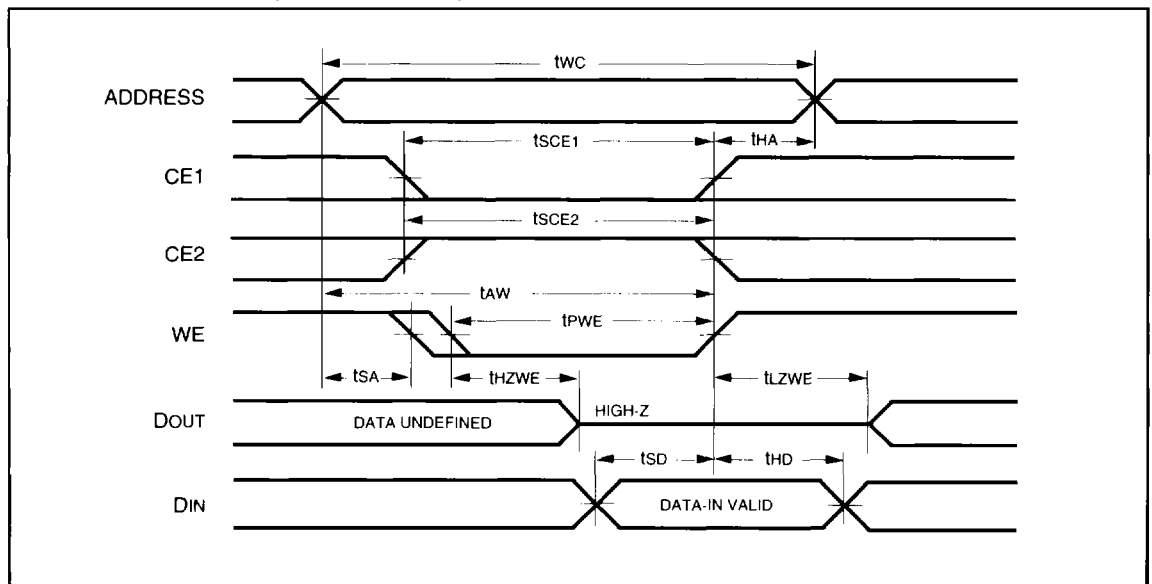
1. \overline{WE} is HIGH for a Read Cycle.
2. The device is continuously selected. \overline{OE} , $\overline{CE1} = V_{IL}$, $CE2 = V_{IH}$.
3. Address is valid prior to or coincident with $\overline{CE1}$ LOW and $CE2$ HIGH transitions.

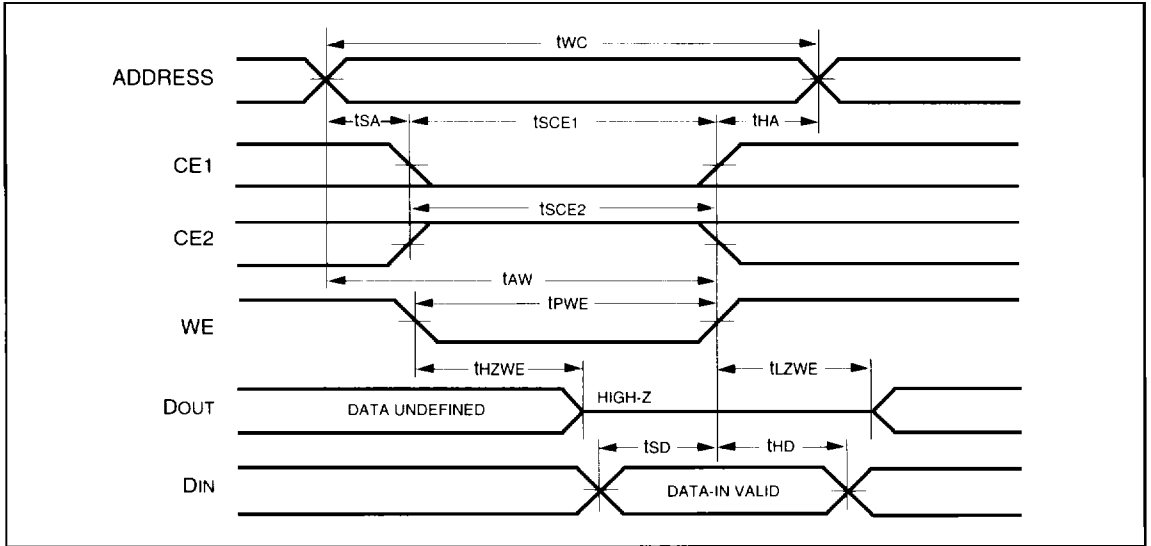
WRITE CYCLE SWITCHING CHARACTERISTICS^(1,3) (Over Operating Range)

Symbol	Parameter	-15 ns		-20 ns		-25 ns		-35 ns		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{WC}	Write Cycle Time	15	—	20	—	25	—	35	—	ns
t _{SCE1}	$\overline{CE1}$ to Write End	12	—	15	—	20	—	30	—	ns
t _{SCE2}	CE2 to Write End	12	—	15	—	20	—	30	—	ns
t _{AW}	Address Setup Time to Write End	12	—	15	—	20	—	30	—	ns
t _{HA}	Address Hold from Write End	0	—	0	—	0	—	0	—	ns
t _{SA}	Address Setup Time	0	—	0	—	0	—	0	—	ns
t _{PWE⁽⁴⁾}	\overline{WE} Pulse Width	10	—	12	—	15	—	20	—	ns
t _{SD}	Data Setup to Write End	8	—	10	—	12	—	15	—	ns
t _{HD}	Data Hold from Write End	0	—	0	—	0	—	0	—	ns
t _{HZWE⁽²⁾}	\overline{WE} LOW to High-Z Output	—	7	—	10	—	12	—	8	ns
t _{LZWE⁽²⁾}	\overline{WE} HIGH to Low-Z Output	2	—	2	—	2	—	2	—	ns

Notes:

1. Test conditions assume signal transition times of 5 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V and output loading specified in Figure 1a.
2. Tested with the load in Figure 1b. Transition is measured ± 500 mV from steady-state voltage. Not 100% tested.
3. The internal write time is defined by the overlap of $\overline{CE1}$ LOW, CE2 HIGH and \overline{WE} LOW. All signals must be in valid states to initiate a Write, but any one can go inactive to terminate the Write. The Data Input Setup and Hold timing are referenced to the rising or falling edge of the signal that terminates the write.
4. Tested with \overline{OE} HIGH.

AC WAVEFORMS**WRITE CYCLE NO. 1 (\overline{WE} Controlled)^(1,2)**

WRITE CYCLE NO. 2 ($\overline{CE1}$, CE2 Controlled)^(1,2)**Notes:**

1. The internal write time is defined by the overlap of $\overline{CE1}$ LOW, CE2 HIGH and \overline{WE} LOW. All signals must be in valid states to initiate a Write, but any one can go inactive to terminate the Write. The Data Input Setup and Hold timing are referenced to the rising or falling edge of the signal that terminates the write.
2. I/O will assume the High-Z state if \overline{OE} = HIGH.

ORDERING INFORMATION: IS61C512**Commercial Range: °C to + 70°C**

Speed (ns)	Order Part No.	Package
15	IS61C512-15J	300-mil SOJ
15	IS61C512-15N	300-mil Plastic DIP
15	IS61C512-15K	400-mil SOJ
15	IS61C512-15M	400-mil Plastic DIP
20	IS61C512-20J	300-mil SOJ
20	IS61C512-20N	300-mil Plastic DIP
20	IS61C512-20K	400-mil SOJ
20	IS61C512-20M	400-mil Plastic DIP
25	IS61C512-25J	300-mil SOJ
25	IS61C512-25N	300-mil Plastic DIP
25	IS61C512-25K	400-mil SOJ
25	IS61C512-25M	400-mil Plastic DIP
35	IS61C512-35J	300 mil SOJ
35	IS61C512-35N	300-mil Plastic DIP
35	IS61C512-35K	400-mil SOJ
35	IS61C512-35M	400-mil Plastic DIP